

Notice of References Cited

Application/Control No.

09/845,934

Applicant(s)/Patent Under

Reexamination

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,134,450	10-2000	Nordeman, Roger Douglas	455/517
	B	US-6,314,301	11-2001	Dorenbosch et al.	455/519
	C	US-6,427,075	07-2002	Burg et al.	455/422
	D	US-6,032,051	02-2000	Hall et al.	455/518
	E	US-6,512,930	01-2003	Sandegren, Per-Arne	455/518
	F	US-6,477,387	11-2002	Jackson et al.	455/519
	G	US-5,613,209	03-1997	Peterson et al.	455/518
	H	US-6,442,396	08-2002	Schmidt et al.	455/518
	I	US-6,240,069	05-2001	Alperovich et al.	370/260
	J	US-6,346,873	02-2002	Suzuki et al.	340/3.41
	K	US-6,484,037	11-2002	Schmidt et al.	455/514
	L	US-6,516,200	02-2003	Schmidt et al.	455/518
	M	US-6,104,925	08-2000	Grube et al.	455/428

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,449,491	09-2002	Dailey, Timothy E.	455/518
	B	US-6,405,035	06-2002	Singh, Mona	455/414
	C	US-6,363,258	03-2002	Schmidt et al.	455/514
	D	US-2002/0102967	08-2002	Chang et al.	455/414
	E	US-2002/0037723	03-2002	Roach, Adam	455/435
	F	US-6,385,461	05-2002	Raith, Alex Krister	455/518
	G	US-6,434,396	08-2002	Rune, Johan	455/502
	H	US-6,449,483	09-2002	Akhteruzzaman et al.	455/445
	I	US-6,501,957	12-2002	Muhonen et al.	455/503
	J	US-6,308,079	10-2001	Pan et al.	455/519
	K	US-6,157,843	12-2000	Derango et al.	455/518
	L	US-6,161,008	12-2000	Lee et al.	455/414
	M	US-6,405,050	06-2002	Amirijoo et al.	455/518

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,850,594	12-1998	Cannon et al.	340/7.21
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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	R					
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	T					

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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